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Multilayered structures InSb_{1-x}Bi_x/InSb-materials for infrared photodetectors

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In the work investigations of electron energy spectrum dependence from thickness (l) and number (N) of layers are carried out as well as treating with rays process in 5–11 layer heterostructures $InSb_{0.97}Bi_{0.03}/InSb$ is considered by kp- and matrix methods. Calculations verified by experiments^[1] show that with an addition of every pair of layers (well/barrier) there is an energy level appearance. N-increasing leads to spectrum displacement into the NIR-field. For thick (l>0.1 mcm) layers its typical high NIR-sensitivity.

Because of the continuity of electromagnetic field tangential constituents at the heteroboundary the transfer matrix Z is single. Through the all multilayer structure Z is the product of Z_i through N_i layers beginning at the side of illumination. With N-increasing there is a rise of the superlattice reflection coefficient R. When $N=11, R\rightarrow 1$, i.e. structure is almost an ideal reflective coating (illumination angle $\alpha=0$, $\lambda=7.7$ and 11 mcm, l=0.1 mcm). For $\alpha=0$ there is a transparency maximum. If N=3, the transparency coefficient $P\rightarrow 0.8$, with N-increasing up to 17P decreases to 0.3. When $\alpha=0-\pi/2$, P=0.8-0. So varying illumination angle one can obtain required P and R without changing of multilayer structure configuration.

Superlattice properties can be used in infrared photodetectors, clarified coatings, heterojunction smoothing to avoid degradation of frequency characteristics and Q-factor because of the energy band gaps in sharp heterojunctions.

References

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